

Release Summary

(AccoTestSTS8200CROSSVersion1100build220419_r p2.0)

New Features

1. Adjust the effective AC level parameter range of ZMU Measure function

Description: The effective AC level parameter range of ZMU Measure function is adjusted to 0.005~1V.

2. Optimization of DVX900 self-check function

Description: The self-check process of IP item is optimized for the DVX900 module.

3. Optimization of INF self-check function

Description: The timeout is optimized for the INF module in the case of a self-check exception.

4. The function that obtained SN information is optimized for the calibration module at STS8200 system

Description: Improve the rules of displaying the SN information of each board in the calibration module.

5. Open the setting function of MDB files larger than 720MB

Description: Supports storage of large test data files. Please refer to the user manual of AccoTEST System Software for details.

6. Add an interface to get the status of whether the site is tested in InitBeforeTestFlow

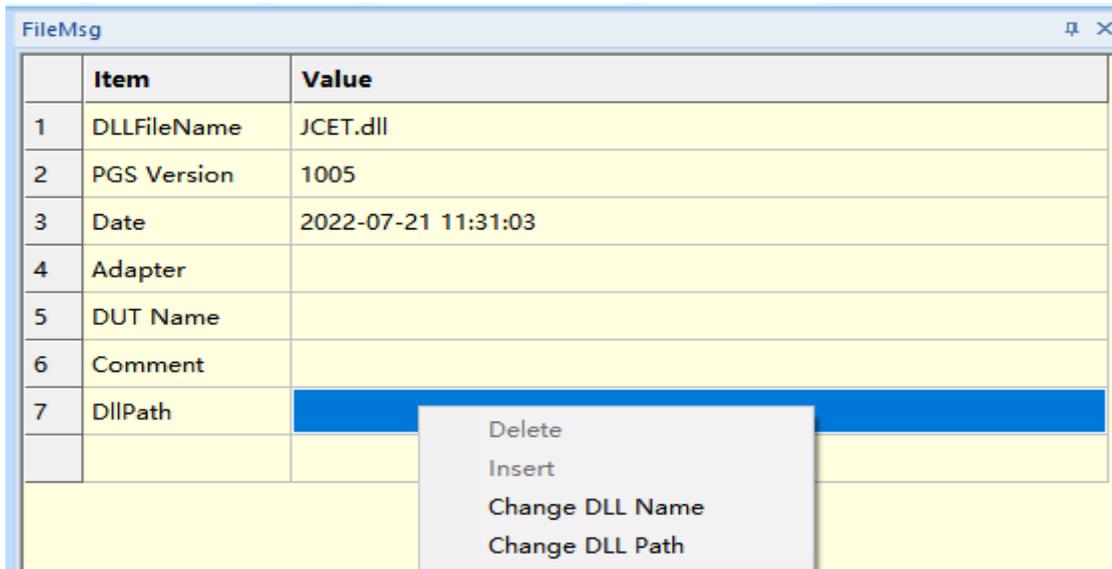
Description: Add STSGetSiteRunStatus to obtain the station to be tested (Intersection of interface setting and sot effective site) .

7. Improve the implementation of test interface function for obtaining LOT information content

Description: Improved interface function STSGetLotInfo to obtain relevant lot information from the upper TestUI in real time.

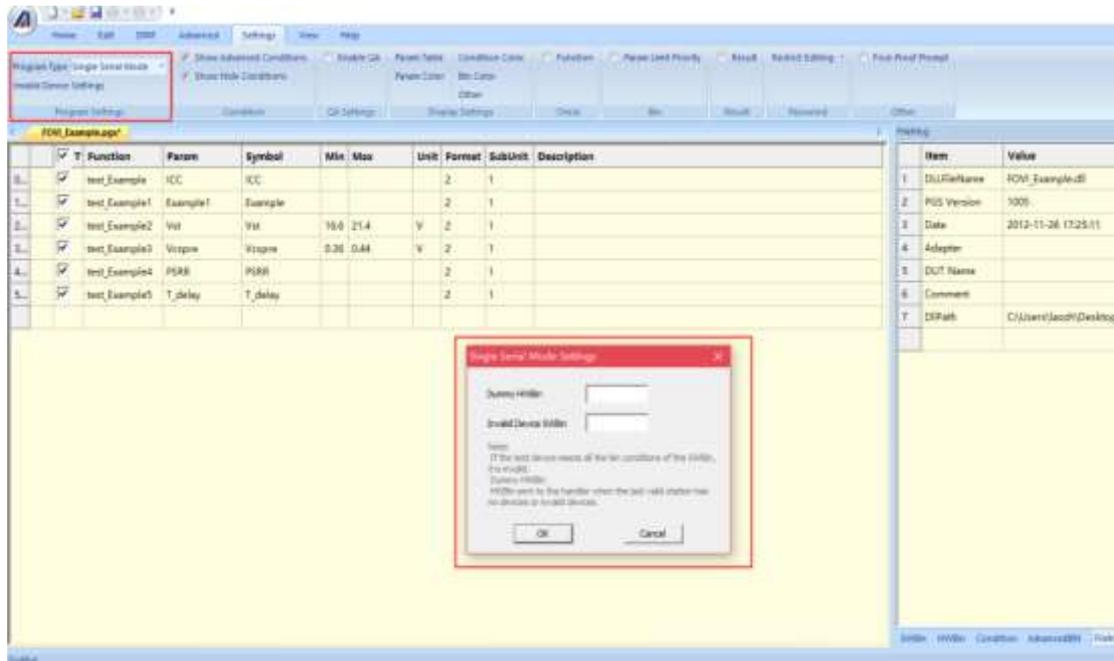
8. PGSEdit 3.0 add DLL path setting

Description: Add DLL path setting. Need to set the full path of DLL file. Directly load the DLL under this path。PGS needs to be upgraded to version 1005.



9. Add Single serial Mode

Description: Add SingleSerialMode. For single sot Mutil-Station. Please refer to the user manual of AccoTEST SYSTEM Software for details.



Fixed Issues

1. SetQAStartFuncNum is not supported in version PGSEdit3.0

Description: SetQAStartFuncNum is not supported.

Risk: QA settings are incorrect.

Solution: Modify QA setting process.

2. The TestUI LOT information is not updated in real time by pasting

Description: The LOT information label was input by pasting in the LOT information setting window interface, but failed to be updated in real time.

Risk: Poor usability.

Solution: Realize the function of pasting and updating lot information label.

3. Invalid keys in PAT setting input box of data analysis software

Description: In the PAT setting window interface of the data analysis software, the function keys of some input boxes are invalid, such as backspace, delete keys, etc.

Risk: Poor usability.

Solution: Remove the restrictions and make the function keys of the input box function normally.

4. The Wafer ID information of TestUI obtained by manual test and automatic test is different

Description: In the LDF file of the test program, the setting of deleting LOT ID information from Wafer ID information is not checked, so the Wafer ID information obtained by manual test is unprocessed Wafer ID information; In the case of automated testing, there is no relevant setting in the Autolot.LDF file. The default value of this setting is true. As a result, during automatic test, the Wafer ID information obtained is the processed Wafer ID information with LOT ID information deleted.

Risk: The Wafer ID information obtained by manual test and automatic test is different.

Solution: Add automation interface functions SetTestProgramSettings and SetSubPath to solve the problem of differentiation.

5. The GetSerialPatternResult of DIO_PLUS get abnormal result

Description: Get serial data result wrong line.

Risk: Acquired data error.

Solution: Modify code.

6. The NewLot operation did not clear the retest information

Description: After NewLot, other devices appear by mistake.

Risk: Other devices appear by mistake.

Solution: NewLot clears device information.

7. Part_ID information coincides with Bin information in Row Mode display mode

Description: When the Part_ID information is long, the Part_ID information coincides with Bin information in Row Mode display mode after test.

Risk: Unable to accurately and quickly view Bin information through the interface.

Solution: Improve the Part_ID display method, which displays the long Part_ID in an abridged way.

8. The test data display is abnormal on different computers in Row Mode display mode

Description: When the number of test parameters exceed 350, some computers display the test data information in blank on Row Mode display mode.

Risk: Test data cannot be displayed correctly.

Solution: Improve display processing.

9. Update problem in PAT settings window of data Analysis Software

Description: In the PAT setting window of data analysis software, according to the generation rule of PAT limit, when the PAT limit is greater than the original limit, a pop-up prompt will appear, but the pat limit have not been updated to the original limit in real time.(This problem is only exist in accoteststs8200crossversion1100build220419_r and later versions)

Risk: The interface display may lead to user misunderstanding, but it does not affect the PAT function.

Solution: Modify the code and continue the interface display processing rules of the old version.

10. Test site display error

Description: Test site display error in TestUI.

Risk: Interface display.

Solution: Modify the returned site status.

11. CheckCode tools affect software permissions

Description: Code analysis tools affect software permissions.

Risk: Affect software use.

Solution: Add version judgment before loading.

12. After the function is copied and pasted, the update operation is abnormal in PGSEdit3.0

Description: After the parameter condition is copied, the update operation causes PGSEdit to exit abnormally.

Risk: Software abnormal exit.

Solution: Modify condition copy process.

13. The test data shown error in offline mapping open in DataAnalyse.exe

Description: Open mapping in DataAnalyse.exe, the test data in mapping is not match with test data actually.

Risk: The testing data in mapping is error.

Solution: Fix bug and solve problem.

14. The SPISetWriteData and SPIRunAllSite of DIO_PLUS class does not take effect

Description: The objects of DIO_PLUS class failed to get during board synchronization.

Risk: Acquired data error.

Solution: Modify code.

15. The layout of the System Option interface is abnormal

Description: In the System Option setting window of Control Software, the button is too close to the bottom.

Risk: The interface layout is awkward, which affects the beauty of the software.

Solution: Adjust the interface layout.

16. The DIO_PLUS class GetSerialPatternResult cannot get the result when StartSynRun runs synchronously.

Description: The objects of DIO_PLUS class failed to obtain correct serial data when synchronizing the running vectors.

Risk: Acquired data error.

Solution: Modify code.

17. The vector editor creates a pin grouping problem with the same name

Description: For the pin group name that already exists in the vector editor, the pin group with the same name is successfully created again.

Risk: There is a pin group with the same name.

Solution: Prohibit creating groups with the same name.

18. Check the problem jump exception in PGSEdit 3.0

Description: Double click the abnormal information of bin, and it does not jump to the correct wrong position.

Risk: No normal jump.

Solution: Modify the position of jump.

19. Failed to modify multi-limit in PGSEdit 3.0

Description: Modifying the limit in use and updating it to TestUI failed

Risk: Update limit loading exception.

Solution: Modify the loading process of limit.

20. Missing multi-BIN column in PGSEdit 3.0

Description: The BIN column is omitted in the process of adjusting the column sequence.

Risk: Don't show BIN.

Solution: Modify column adjustment logic.

21. The return value of GetDispFormat is different on PGSEdit1.0 and 3.0 versions

Description: Return 0. on PGSEdit1.0. Return 0 on PGSEdit3.0.

Risk: Version difference.

Solution: Modify return value.

22. Abnormal retest after changing site enable status

Description: After the test, enter option, change the status of some site form disable status to enable status, then start the retest. The TestUI will prompt and prohibit the retest.

Risk: Poor usability.

Solution: Improve the retest process processing, allowing the conditions

described above to be retested correctly.

23. The optional condition units and values are missing when adding functions from the template in PGSEdit3.0

Description: The optional condition units and values are missing when adding functions from the template.

Risk: Poor usability.

Solution: Improve add operations.

24. False triggering of stacking alarm

Description: When the stacking test control function is selected, and the application scope of SPL is all sites, some sites that are not tested will trigger stacking alarms incorrectly.

Risk: The stacking alarm is triggered by mistake.

Solution: Because of its particularity, the stacking test control is applicable to the site only when the sampling number of the current site is greater than the minimum sampling number.